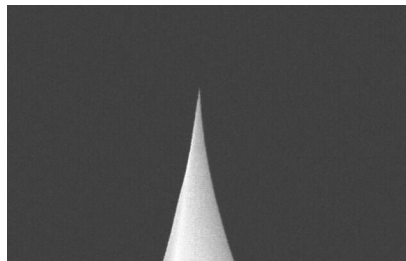


# SHOCONA-SS

SHOCONA-SS probes are Super-Sharp silicon probes designed for contact mode applications. These probes feature shorter cantilevers, which provide better sensitivity without compromising on spring constant requirements. Our Super Sharp probes yield enhanced resolution images, and have Aluminum coating on the reflex side to increase laser signal quality.

## Tip Specifications

- **Material:** Silicon
- **Shape:** Pyramidal
- **Height ( $\mu\text{m}$ ):** 14-16
- **Aspect ratio:** >3.5
- **ROC (nm) :** 2
- **Coating:** None



### SHOCONA-SS

On click zoom images

[Download Spec](#)

## Cantilever Specifications

Material: Silicon

Shape : Rectangular

Reflex coating : Al, 50 nm  $\pm$  5

Parameter	Nominal	Min	Max
k (N/m)	0.14	0.01	0.60
f (kHz)	21.0	8.0	37.0
Length ( $\mu\text{m}$ )	225.0	215.0	235.0
Width ( $\mu\text{m}$ )	46.0	41.0	51.0
Thickness ( $\mu\text{m}$ )	1.00	0.50	1.50